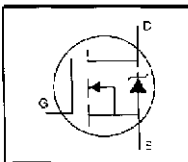


**HEXFET® Power MOSFET**

- Ultra Low Gate Charge
- Reduced Gate Drive Requirement:
- Enhanced 30V V<sub>GS</sub> Rating
- Reduced C<sub>iss</sub>, C<sub>oss</sub>, C<sub>rss</sub>
- Extremely High Frequency Operation
- Repetitive Avalanche Rated

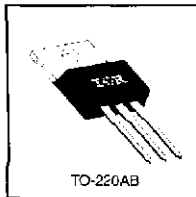


$V_{DSS} = 600V$
$R_{DS(on)} = 1.2\Omega$
$I_D = 6.2A$

**Description**

This new series of Low Charge HEXFETs achieve significantly lower gate charge over conventional MOSFETs. Utilizing the new LCDMOS technology, the device improvements are achieved without added product cost, allowing for reduced gate drive requirements and total system savings. In addition reduced switching losses and improved efficiency are achievable in a variety of high frequency applications. Frequencies of a few MHz at high current are possible using the new Low Charge MOSFETs.

These device improvements combined with the proven ruggedness and reliability that are characteristic of HEXFETs offer the designer a new standard in power transistors for switching applications.



**Absolute Maximum Ratings**

Parameter	Max.	Units
$I_D @ T_C = 25^\circ C$ Continuous Drain Current, V <sub>GS</sub> @ 10 V	6.2	A
$I_D @ T_C = 100^\circ C$ Continuous Drain Current, V <sub>GS</sub> @ 10 V	3.9	A
$I_{DM}$ Pulsed Drain Current (†)	25	A
$P_D @ T_C = 25^\circ C$ Power Dissipation	125	W
Linear Derating Factor	1.0	W/°C
V <sub>GS</sub> Gate-to-Source Voltage	±30	V
E <sub>AS</sub> Single Pulse Avalanche Energy (‡)	530	mJ
I <sub>AS</sub> Avalanche Current (‡)	6.2	A
E <sub>AR</sub> Repetitive Avalanche Energy (‡)	13	mJ
dv/dt Peak Diode Recovery dv/dt (‡)	3.0	V/ns
T <sub>J</sub> Operating Junction and Storage Temperature Range	-55 to +150	°C
T <sub>SOLD</sub> Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
Mounting Torque, 6-32 or M3 screw	10 lbf-in (1.1 N-m)	

**Thermal Resistance**

Parameter	Min.	Typ.	Max.	Units
R <sub>θJC</sub> Junction-to-Case	—	—	1.0	°C/W
R <sub>θCS</sub> Case-to-Sink, Flat, Greased Surface	—	0.50	—	°C/W
R <sub>θJA</sub> Junction-to-Ambient	—	—	62	°C/W

# IRFBC40LC



## Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

Parameter	Parameter	Min.	Typ.	Max.	Units	Test Conditions
V <sub>GS(BOSS)</sub>	Drain-to-Source Breakdown Voltage	600	—	—	V	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA
ΔV <sub>BR(BOSS)/ΔT<sub>J</sub></sub>	Breakdown Voltage Temp. Coefficient	—	0.70	—	V/°C	Reference to 25°C, I <sub>D</sub> =1mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance	—	—	1.2	Ω	V <sub>GS</sub> =10V, I <sub>D</sub> =3.7A ④
V <sub>GS(th)</sub>	Gate Threshold Voltage	2.0	—	4.0	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA
g <sub>fs</sub>	Forward Transconductance	3.7	—	—	S	V <sub>GS</sub> =100V, I <sub>D</sub> =3.7A ④
I <sub>DSS</sub>	Drain-to-Source Leakage Current	—	—	100	μA	V <sub>DS</sub> =800V, V <sub>GS</sub> =0V V <sub>DS</sub> =480V, V <sub>GS</sub> =0V, T <sub>J</sub> =125°C
I <sub>DSS</sub>	Gate-to-Source Forward Leakage	—	—	100	nA	V <sub>GS</sub> =20V
I <sub>DSS</sub>	Gate-to-Source Reverse Leakage	—	—	-100	nA	V <sub>GS</sub> =-20V
Q <sub>g</sub>	Total Gate Charge	—	—	39	nC	I <sub>D</sub> =6.2A
Q <sub>gs</sub>	Gate-to-Source Charge	—	—	9	nC	V <sub>DS</sub> =360V
Q <sub>gd</sub>	Gate-to-Drain Miller Charge	—	—	9	nC	V <sub>GS</sub> =10V See Fig. 6 and 13 ④
t <sub>turn(on)</sub>	Turn-On Delay Time	—	12	—	ns	V <sub>DD</sub> =300V
t <sub>r</sub>	Rise Time	—	20	—	ns	I <sub>D</sub> =6.2A
t <sub>turn(off)</sub>	Turn-Off Delay Time	—	27	—	ns	R <sub>θ</sub> =9.1Ω
t <sub>f</sub>	Fall Time	—	17	—	ns	R <sub>θ</sub> =4711 See Figure 10 ④
L <sub>D</sub>	Internal Drain Inductance	—	4.5	—	nH	Between lead, 6 mm (0.25in.) from package and center of the contact
L <sub>S</sub>	Internal Source Inductance	—	7.5	—	nH	
C <sub>iss</sub>	Input Capacitance	—	1100	—	pF	V <sub>GS</sub> =0V
C <sub>oss</sub>	Output Capacitance	—	140	—	pF	V <sub>DS</sub> =25V
C <sub>rss</sub>	Reverse Transfer Capacitance	—	15	—	pF	f=1.0MHz See Figure 5

## Source-Drain Ratings and Characteristics

Parameter	Parameter	Min.	Typ.	Max.	Units	Test Conditions
I <sub>S</sub>	Continuous Source Current (Body Diode)	—	—	6.2	A	MOSFET symbol showing the integral reverse p-n junction diode.
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ④	—	—	25	A	
V <sub>SD</sub>	Diode Forward Voltage	—	—	1.5	V	T <sub>J</sub> =25°C, I <sub>S</sub> =6.2A, V <sub>GS</sub> =0V ④
t <sub>r</sub>	Reverse Recovery Time	—	440	680	ns	T <sub>J</sub> =25°C, I <sub>F</sub> =6.2A
Q <sub>r</sub>	Reverse Recovery Charge	—	2.1	3.2	μC	dI/dt=100A/μs ④
t <sub>on</sub>	Forward Turn-On Time	Minimum turn-on time is negligible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )				

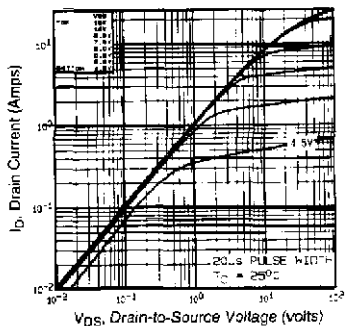
### Notes:

① Repetitive rating; pulse width limited by max. junction temperature (See Figure 11)

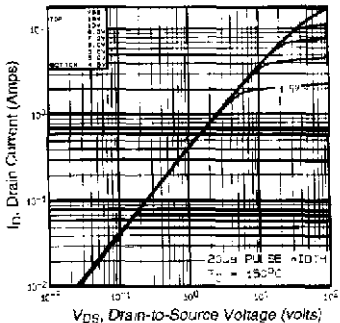
② V<sub>DD</sub>=50V, starting T<sub>J</sub>=25°C, L=25mH, R<sub>θ</sub>=25Ω, I<sub>AS</sub>=6.2A (See Figure 12)

③ I<sub>SD</sub>=6.2A, dI/dt=80A/μs, V<sub>DD</sub>=V<sub>BR(BOSS)</sub>, T<sub>J</sub>≤150°C

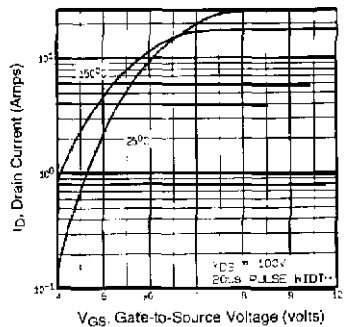
④ Pulse width ≤ 300 μs; duty cycle ≤ 2%



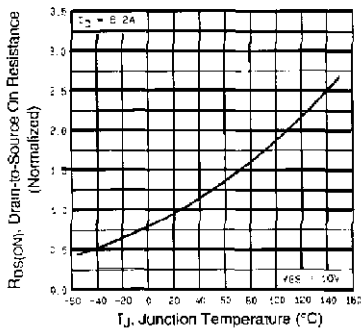
**Fig 1.** Typical Output Characteristics.  
 $T_C=25^\circ\text{C}$



**Fig 2.** Typical Output Characteristics.  
 $T_C=150^\circ\text{C}$



**Fig 3.** Typical Transfer Characteristics



**Fig 4.** Normalized On-Resistance  
Vs. Temperature

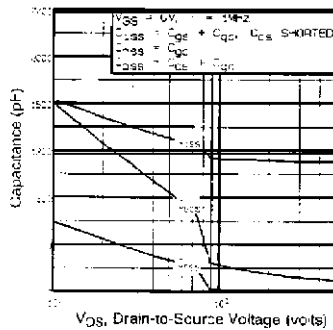


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

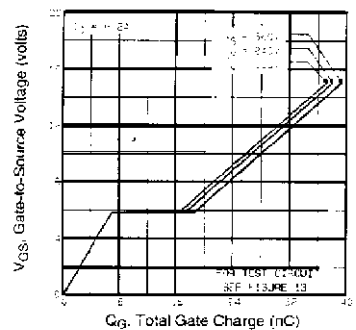


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

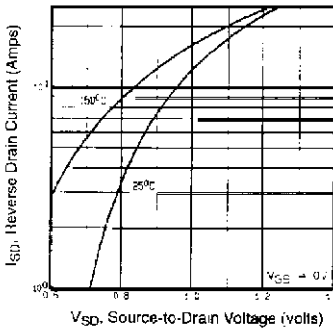


Fig 7. Typical Source-Drain Diode Forward Voltage

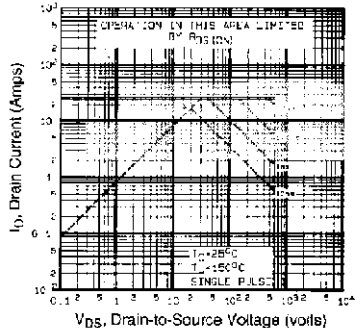


Fig 8. Maximum Safe Operating Area

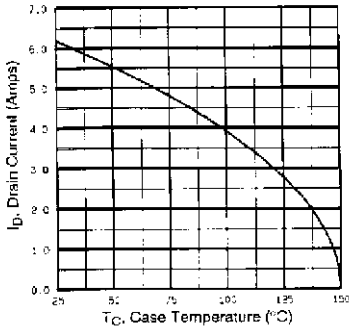


Fig 9. Maximum Drain Current Vs. Case Temperature

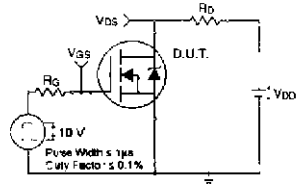


Fig 10a. Switching Time Test Circuit

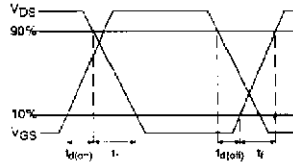


Fig 10b. Switching Time Waveforms

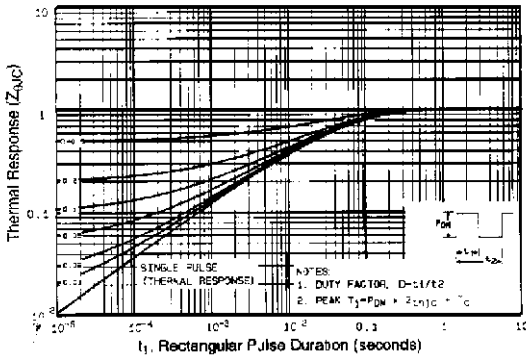
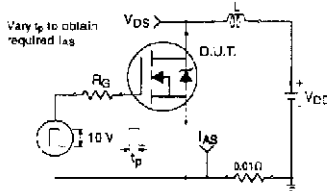
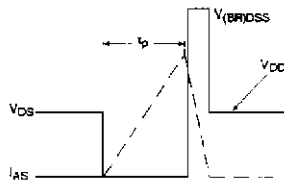


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

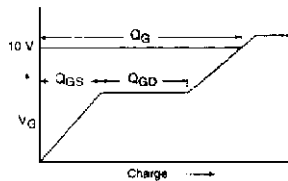
# IRFBC40LC



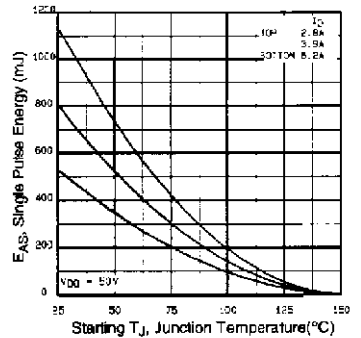
**Fig 12a.** Unclamped Inductive Test Circuit



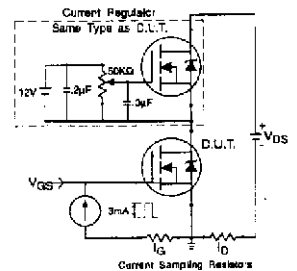
**Fig 12b.** Unclamped Inductive Waveforms



**Fig 13a.** Basic Gate Charge Waveform



**Fig 12c.** Maximum Avalanche Energy Vs. Drain Current



**Fig 13b.** Gate Charge Test Circuit

**Appendix A:** Figure 14, Peak Diode Recovery  $dv/dt$  Test Circuit

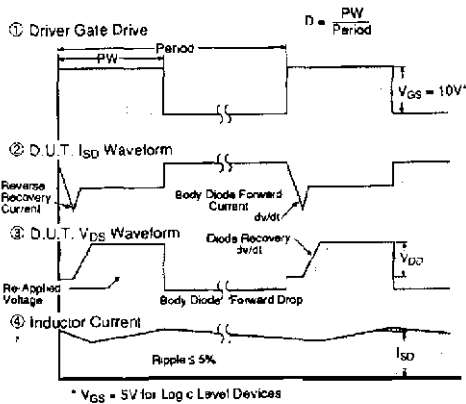
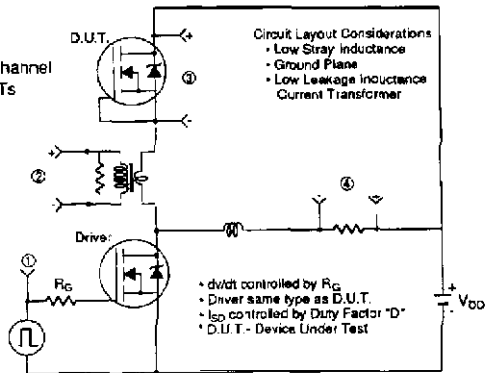
**Appendix B:** Package Outline Mechanical Drawing

**Appendix C:** Part Marking Information

## Appendix A

### Peak Diode Recovery $dv/dt$ Test Circuit

**Fig 14.** For N-Channel HEXFETs



# IRFBC40LC

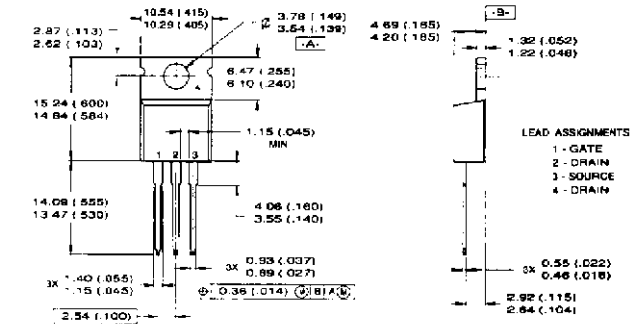


## Package Outline

## Appendix B

### TO-220AB Outline

Dimensions are shown in millimeters (inches)



- LEAD ASSIGNMENTS
- 1 - GATE
  - 2 - DRAIN
  - 3 - SOURCE
  - 4 - DRAIN

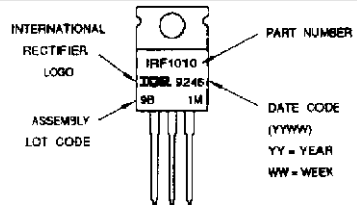
- NOTES:
- 1 DIMENSIONING & TOLERANCING PER ANSI Y14.5M 1992
  - 2 CONTROLLING DIMENSION: DICH
  - 3 OUTLINE CONFORMS TO JEDEC OUTLINE TO-220AB
  - 4 HEATSINK & LEAD MEASUREMENTS DO NOT INCLUDE BURRS.

## Part Marking Information

## Appendix C

### TO-220AB

EXAMPLE: THIS IS AN IRF1010 WITH  
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